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10/781,819	UEDA ET AL.	
Examiner	Art Unit	
Tan V. Mai	2193	

	SEARCHED				
Class	Subclass	Date	Examiner		
708	3, 250, 255, 801	7/9/2008	MAI		

INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	7/9/2008	MAI		